

**Search Notes**

Application/Control No.

09/621,476

Examiner

Minh Dieu Nguyen

Applicant(s)/Patent under  
Reexamination

KAHN ET AL.

Art Unit

2137

**SEARCHED**

Class	Subclass	Date	Examiner
380	201, 239-240	1/6/2006	MDN
705	51-52	1/6/2006	MDN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
380	201	1/6/2006	MDN
705	51	1/6/2006	MDN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated text and class search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	1/6/2006	MDN
Updated inventor name search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	1/6/2006	MDN
Primary examiner M. Smithers suggested to look at Son's US patents	1/18/2006	MDN